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Silicon Epitaxial Planar Switching Diode





SOD123FL SOD123GW

1N4148W Package SOD-123(GW) 1N4148W-FL Package SOD-123FL

Surface mount Plastic Package RoHS compliant

FEATURES:

- 1. Fast Switching
- 2. SOD-123
- 3. These diodes are also available in other case style including the DO-35 case with the type designation 1N4148, the MiniMELF case with the type designation LL4148 and the MicroMELF case type designation LL4148 and the MicroMELF case with the type designation MCL4148.
- 4. This product is available in AEC-Q101 Compliant also.
- 5. **Note:** For AEC-Q101 compliant product, please suffix AQ iin the part number while ordering.

Absolute Maximum Ratings (T_A = 25°C)

Parameter		Symbol	Value	Unit	
Peak Reverse Voltage		V_{RM}	100	V	
Reverse Voltage		V_R	75	V	
Average Rectified Forward Curre		I _{F(AV)}	150	mA	
	at t = 1 s		0.5		
Non-repetitive Peak Forward Surge Current	at t = 1 ms	I _{FSM}	1	Α	
	at t = 1 µs		4		
Power Dissipation		P _{tot}	400	mW	
Thermal Resistance from Junction to Ambient Air		$R_{\theta JA}$	312	°C/W	
Junction Temperature		T _j	150	°C	
Storage Temperature Range		T_{stg}	-65 to +150	°C	







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ELECTRICAL CHARACTERISTICS at T_a = 25 $^{\circ}\mathrm{C}$

Parameter	Symbol	Test Conditions	Value			Unit
Parameter		rest Conditions	Min.	Тур.	Max.	Unit
Reverse Breakdown Voltage	$V_{(BR)}$	at I _R = 1 µA	75			
Forward Voltage	V _F	at IF = 1 mA			0.72	
		at IF = 10 mA			0.86	V
		at IF = 50 mA			1.00	
		at IF = 150 mA			1.20	
Peak Reverse Current	I _R	at VR = 75 V	-		1	μΑ
		at VR = 20 V	-		25	nA
		at V _R =75 V @T _J 150°C	1		50	μΑ
		at V _R =25 V@T _J 150°C	1		30	μΑ
Total Capacitance	C_T	at $V_R = 0 V$, $f = 1 MHz$	-		2	pF
Reverse Recovery Time	t _{rr}	at $I_F = 10 \text{ mA}, I_R = 1 \text{ mA},$			4	nS









Typical Characteristic test circuit and curves

Fig 1. Test Circuit for Rectification Efficency Measurement

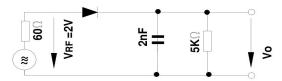


Fig 2. Forward Characteristics

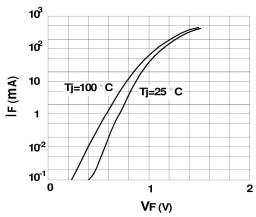


Fig 3. Power Dissipation vs. Ambient Temperature

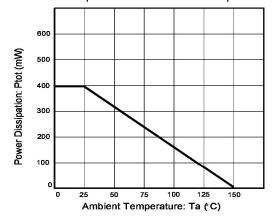


Fig 4. Leakage Current vs. Junction Temperature

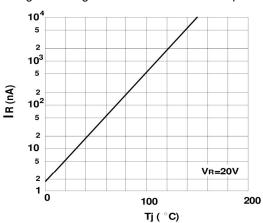
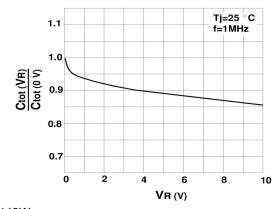


Fig 5. Reverse Capacitance vs. Reverse Voltage



1N4148W



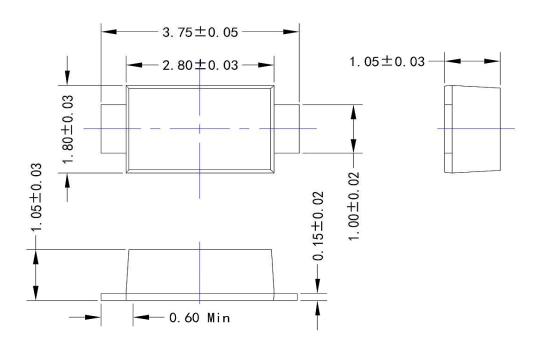
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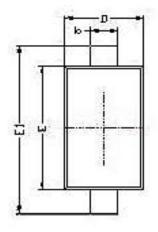


Package Details

Package SOD123FL

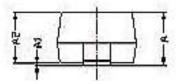


Package SOD123GW



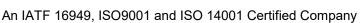


SYMBOL	Dimensions		
STWIBOL	Min.	Max.	
Α	1.050	1.250	
A1	0.000	0.100	
A2	1.050	1.150	
b	0.450	0.650	
С	0.080	0.150	
D	1.500	1.700	
E	2.600	2.800	
E1	3.550	3.850	
L	0.500 Ref.		
L1	0.250	0.450	
θ	0°	8°	



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Recommended Product Storage Environment for Discrete Semiconductor Devices

This storage environment assumes that the Diodes and transistors are packed properly inside the original packing supplied by CDIL.

- · Temperature 5 °C to 30 °C
- · Humidity between 40 to 70 %RH
- · Air should be clean.
- · Avoid harmful gas or dust.
- · Avoid outdoor exposure or storage in areas subject to rain or water spraying .
- · Avoid storage in areas subject to corrosive gas or dust. Product shall not be stored in areas exposed to direct sunlight.
- · Avoid rapid change of temperature.
- · Avoid condensation.
- · Mechanical stress such as vibration and impact shall be avoided.
- · The product shall not be placed directly on the floor.
- · The product shall be stored on a plane area. They should not be turned upside down.

They should not be placed against the wall.

Shelf Life of CDIL Products

The shelf life of products is the period from product manufacture to shipment to customers. The product can be unconditionally shipped within this period. The period is defined as 2 years.

If products are stored longer than the shelf life of 2 years the products shall be subjected to quality check as per CDIL quality procedure.

The products are further warranted for another one year after the date of shipment subject to the above conditions in CDIL original packing.

Floor Life of CDIL Products and MSL Level

When the products are opened from the original packing, the floor life will start.

For this, the following JEDEC table may be referred:

JEDEC MSL Level			
Level	Time	Condition	
1	Unlimited	≤30 °C / 85% RH	
2	1 Year	≤30 °C / 60% RH	
2a	4 Weeks	≤30 °C / 60% RH	
3	168 Hours	≤30 °C / 60% RH	
4	72 Hours	≤30 °C / 60% RH	
5	48 Hours	≤30 °C / 60% RH	
5a	24 Hours	≤30 °C / 60% RH	
6	Time on Label(TOL)	≤30 °C / 60% RH	

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Customer Notes

Component Disposal Instructions

- 1. CDIL Semiconductor Devices are RoHS compliant, customers are requested to please dispose as per prevailing Environmental Legislation of their Country.
- 2. In Europe, please dispose as per EU Directive 2002/96/EC on Waste Electrical and Electronic Equipment (WEEE).

Disclaimer

The product information and the selection guides facilitate selection of the CDIL's Semiconductor Device(s) best suited for application in your product(s) as per your requirement. It is recommended that you completely review our Data Sheet(s) so as to confirm that the Device(s) meet functionality parameters for your application. The information furnished in the Data Sheet and on the CDIL Web Site/CD are believed to be accurate and reliable. CDIL however, does not assume responsibility for inaccuracies or incomplete information. Furthermore, CDIL does not assume liability whatsoever, arising out of the application or use of any CDIL product; neither does it convey any license under its patent rights nor rights of others. These products are not designed for use in life saving/support appliances or systems. CDIL customers selling these products (either as individual Semiconductor Devices or incorporated in their end products), in any life saving/support appliances or systems or applications do so at their own risk and CDIL will not be responsible for any damages resulting from such sale(s).



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